

<b>Notice of References Cited</b>	Application/Control No. 10/575,049	Applicant(s)/Patent Under Reexamination DE KRETSE ET AL.	
	Examiner Maher M. Haddad	Art Unit 1644	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0162715	08-2003	Duan et al.	514/12
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
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	N	WO 03/006057	01-2003	PCT	PHILLIPS et al	
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**NON-PATENT DOCUMENTS**

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